

**Notice of References Cited**

Application/Control No.

09/925,486

Applicant(s)/Patent Under  
Reexamination  
EGUCHI ET AL.

Examiner

A. Sefer

Art Unit

2826

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,392,255	05-2002	Shibata et al	257/59
	B	US-5,946,060	08-1999	Nishiki et al	349/48
	C	US-2001/0040656	11-2001	Na et al	349/110
	D	US-6,278,503	08-2001	Nishikawa et al	349/39
	E	US-5,734,177	03-1998	Sakamoto	257/49
	F	US-6,476,898	11-2002	Song et al	349/139
	G	US-2002/0044244	04-2002	Lee	349/141
	H	US-5,672,888	09-1997	Nakamura	257/72
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 450 941	10-1991	European	Shimada et al	
	O	JP 7-28089	01-1995	Japan	Mizobata et al	
	P	JP 6-148678	05-1994	Japan	Kitawada et al	
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.